addenda and errata



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Determination of X-ray pulse duration via intensity correlation measurement of X-ray fluorescence. Erratum

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Corrections to equations and experimental results in the paper by Inoue *et al.* [(2019). *J. Synchrotron Rad.* **26**, 2050–2054] are made.

The correct versions of equations (2) and (3) in the paper by Inoue *et al.* (2019) are as follows:

$$g_{f}^{(2)}(r_{1}, r_{2}) = 1 + \frac{1}{2} \left| j(r_{1}, r_{2}) \right|^{2} \int \Pi(\tau) \left| \gamma(\tau) \right|^{2} d\tau, \qquad (2)$$

$$g_f^{(2)}(r_1, r_2) = 1 + \frac{1}{2}g_0^{(2)}\exp\left(-\frac{\Delta x^2}{2l_x^2}\right)\exp\left(-\frac{\Delta y^2}{2l_y^2}\right).$$
 (3)

The additional factors of 1/2 on the right-hand sides of these equations represent a decrease in intensity correlation of X-ray fluorescence due to the unpolarized nature of the fluorescence (Trost *et al.*, 2020; Goodman, 2007).

Accordingly, the degree of intensity correlation $[g_0^{(2)}]$ and the XFEL duration $[2\sqrt{2 \ln 2} \sigma_t]$ evaluated by the experiment also need to be corrected; the values of $g_0^{(2)}$ and $2\sqrt{2 \ln 2} \sigma_t$ shown in Section 4 should be 0.0262 ± 0.008 and 5.1 ± 0.2 fs, respectively. The determined XFEL duration is consistent with previous estimations by other methods (Inubushi *et al.*, 2017; Inoue *et al.*, 2018), in which the XFEL duration was evaluated to be less than 10 fs. Although the determined XFEL duration is shorter than the electron bunch duration measured by a radiofrequency deflector (~10 fs in FWHM), such discrepancy could be explained by insufficient time resolution of the deflector (~10 fs) (Ego *et al.*, 2015).

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